AEROSPACE DATA EXCHANGE PROGRAM TRANSMITTAL
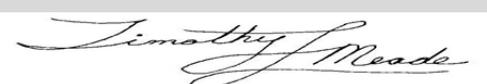
PRODUCT CHANGE NOTICE

CAES

1. TITLE MICROCIRCUIT, DIGITAL, CMOS, SERIAL MICROCODED MULTI-MODE INTELLIGENT TERMINAL AND TRANSCEIVER, SILICON	**2. DOCUMENT NUMBER** SPO-2013-PCN-0006

3. DATE *(Year, Month, Date)*
2013 May 17

4. MANUFACTURER NAME AND ADDRESS CAES 4350 CENTENNIAL BOULEVARD COLORADO SPRINGS, COLORADO 80907-3486	**5. MANUFACTURER POINT OF CONTACT NAME** Tim Meade, CAES
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	7. MANUFACTURER POINT OF CONTACT EMAIL tim.l.meade@cobhamaes.com

8. CAGE CODE 65342	**9. EFFECTIVE DATE** 2013 May 17	**10. PRODUCT IDENTIFICATION CODE** MM004, MM005, MM023, MM024, MM027	**11. BASE PART** UT69151DXE UT69151LXE15
12. BLANK		**13. SMD NUMBER** 5962-94663	**14. DEVICE TYPE DESIGNATOR** -04, -05, -10, -11
		15. RHA LEVELS ALL	**16. QML LEVEL** Q and V
		17. NON QML LEVEL N/A	**18. BLANK**

19. PRODUCT CHANGE

Background:

The MICROCIRCUIT, DIGITAL, CMOS, RADIATION HARDENED, SERIAL MICROCODED MULTI-MODE INTELLIGENT TERMINAL AND TRANSCEIVER, SILICON is a multi-chip module (MCM) containing one MIL-STD-1553 protocol die and two MIL-STD-1553 transceiver dice.

The standard microcircuit drawing (SMD) was originated in 1993. Since that time the wafer fab used to produce the protocol die and transceiver dice has changed. As a result, device types have been added to the SMD to distinguish the differences in performance including the total ionizing dose (TID) performance. To be consistent with the format of new SMDs, device types -04, -05, -10, and -11 are now updated with single event effects (SEE) information.

In the Rev. J SMD, "single event phenomenon (SEP) effective" was specified as "linear energy threshold (LET), no upsets." The specified number in the document was the single event upset (SEU) linear energy transfer threshold (LETTH = 0.25) defined as the LET at 25% of the saturated cross-section, which is not the same as the "no upset" number. The SEU onset LET numbers (no upset) have been incorporated into the document for device types -04, -05, -10, and -11.

Details of Change:

Change title from: MICROCIRCUIT, DIGITAL, CMOS, SERIAL MICROCODED MULTI-MODE INTELLIGENT TERMINAL AND TRANSCEIVER, SILICON

Change title to: MICROCIRCUIT, DIGITAL, CMOS, RADIATION HARDENED, SERIAL MICROCODED MULTI-MODE INTELLIGENT TERMINAL AND TRANSCEIVER, SILICON

SEP "No SEL" numbers have been specified in the document for device types -04, -05, -10, and -11 and are the minimum tested LET numbers for the protocol device and the transceiver.

SEP "No SEU" numbers have been specified in the document for device types -04, -05, -10, and -11. These numbers relate only to the protocol device with memory storage elements, since the transceiver devices do not have memory storage elements to upset. These numbers are the SEU onset LET numbers rather than LETTH at 25% of the saturated cross section.

20. DISPOSITIONARY RECOMMENDATION:	CHECK & USE AS IS ☒	CONTACT MANUFACTURER ☐	REMOVE & REPLACE ☐	CORRECT & USE AS SPECIFIED ☐
21. ADEPT REPRESENTATIVE Timothy L. Meade	**22. SIGNATURE** *Timothy L. Meade*			**23. DATE** 2013 May 24